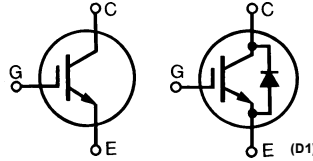


# HiPerFAST™ IGBT ISOPLUS247™ (Electrically Isolated Backside)

IXGR 40N60C  
IXGR 40N60CD1

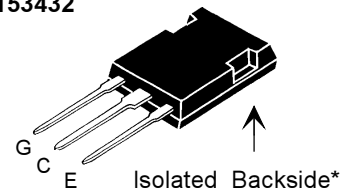
$V_{CES} = 600 \text{ V}$   
 $I_{C25} = 75 \text{ A}$   
 $V_{CE(sat)} = 2.5 \text{ V}$   
 $t_{fi(typ)} = 75 \text{ ns}$



Symbol	Test Conditions	Maximum Ratings	
$V_{CES}$	$T_J = 25^\circ\text{C to } 150^\circ\text{C}$	600	V
$V_{CGR}$	$T_J = 25^\circ\text{C to } 150^\circ\text{C}; R_{GE} = 1 \text{ M}\Omega$	600	V
$V_{GES}$	Continuous	$\pm 20$	V
$V_{GEM}$	Transient	$\pm 30$	V
$I_{C25}$	$T_C = 25^\circ\text{C}$	75	A
$I_{C110}$	$T_C = 110^\circ\text{C}$	35	A
$I_{CM}$	$T_C = 25^\circ\text{C}, 1 \text{ ms}$	150	A
<b>SSOA (RBSOA)</b>	$V_{GE} = 15 \text{ V}, T_{VJ} = 125^\circ\text{C}, R_G = 10 \Omega$ Clamped inductive load	$I_{CM} = 80$ @ $0.8 V_{CES}$	A
$P_c$	$T_C = 25^\circ\text{C}$	200	W
$T_J$		-55 ... +150	$^\circ\text{C}$
$T_{JM}$		150	$^\circ\text{C}$
$T_{stg}$		-55 ... +150	$^\circ\text{C}$
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	$^\circ\text{C}$
$M_d$	Mounting torque (M3)	1.13/10Nm/lb.in.	
<b>Weight</b>		5	g

## ISOPLUS 247

E153432



G = Gate, C = Collector  
E = Emitter

\* Patent pending

## Features

- DCB Isolated mounting tab
- Meets TO-247AD package Outline
- High current handling capability
- Latest generation HDMOS™ process
- MOS Gate turn-on - drive simplicity

## Applications

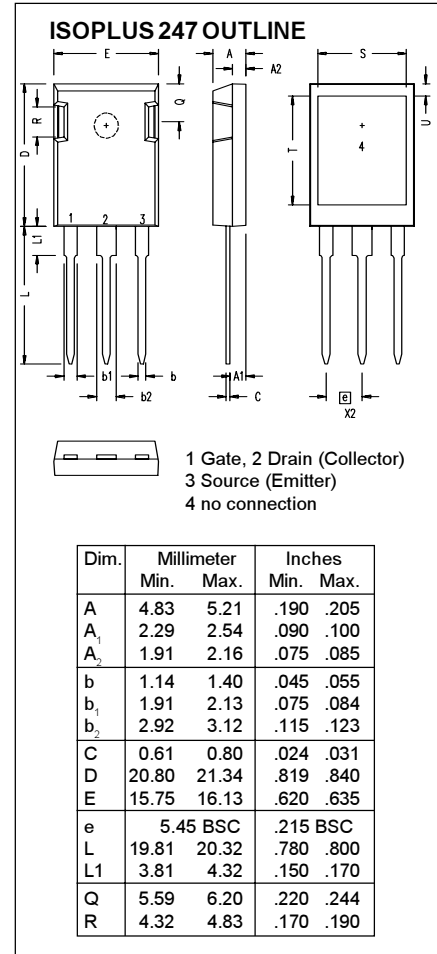
- Uninterruptible power supplies (UPS)
- Switched-mode and resonant-mode power supplies
- AC motor speed control
- DC servo and robot drives
- DC choppers

## Advantages

- Easy assembly
- High power density
- Very fast switching speeds for high frequency applications

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		Min.	Typ.	Max.
$BV_{CES}$	$I_C = 250 \mu\text{A}, V_{GE} = 0 \text{ V}$ $I_C = 750 \mu\text{A}$	40N60C 600		V
		40N60CD1 600		
$V_{GE(th)}$	$I_C = 250 \mu\text{A}, V_{CE} = V_{GE}$ $I_C = 500 \mu\text{A}$	40N60C 2.5		5.0 V
		40N60CD1 2.5		5.0 V
$I_{CES}$	$V_{CE} = 0.8 \cdot V_{CES}, T_J = 25^\circ\text{C}$ $V_{GE} = 0 \text{ V}; \text{note 1 } T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$ $T_J = 125^\circ\text{C}$	40N60C 40N60CD1 40N60C 40N60CD1		200 $\mu\text{A}$ 650 $\mu\text{A}$ 1 mA 3 mA
$I_{GES}$	$V_{CE} = 0 \text{ V}, V_{GE} = \pm 20 \text{ V}$			$\pm 100 \text{ nA}$
$V_{CE(sat)}$	$I_C = I_T, V_{GE} = 15 \text{ V}$			2.5 V

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		min.	typ.	max.
$g_{fs}$	$I_C = I_T$ ; $V_{CE} = 10\text{ V}$ , Pulse test, $t \leq 300\text{ }\mu\text{s}$ , duty cycle $\leq 2\%$	30	40	S
$C_{ies}$	$V_{CE} = 25\text{ V}$ , $V_{GE} = 0\text{ V}$ , $f = 1\text{ MHz}$	3300		pF
$C_{oes}$		310		pF
$C_{res}$		370		pF
$C_{res}$		65		pF
$Q_g$	$I_C = I_T$ , $V_{GE} = 15\text{ V}$ , $V_{CE} = 0.5 V_{CES}$	116		nC
$Q_{ge}$		23		nC
$Q_{gc}$		55		nC
$t_{d(on)}$	<b>Inductive load, <math>T_J = 25^\circ\text{C}</math></b> $I_C = I_T$ , $V_{GE} = 15\text{ V}$ $V_{CE} = 0.8 \cdot V_{CES}$ , $R_G = R_{off} = 4.7\text{ }\Omega$ Remarks: Switching times may increase for $V_{CE}(\text{Clamp}) > 0.8 \cdot V_{CES}$ , higher $T_J$ or increased $R_G$	25		ns
$t_{ri}$		30		ns
$t_{d(off)}$		100	150	ns
$t_{fi}$		75	150	ns
$E_{off}$		0.85	1.70	mJ
$t_{d(on)}$	<b>Inductive load, <math>T_J = 125^\circ\text{C}</math></b> $I_C = I_T$ , $V_{GE} = 15\text{ V}$ $V_{CE} = 0.8 \cdot V_{CES}$ , $R_G = R_{off} = 4.7\text{ }\Omega$ Remarks: Switching times may increase for $V_{CE}(\text{Clamp}) > 0.8 \cdot V_{CES}$ , higher $T_J$ or increased $R_G$	25		ns
$t_{ri}$		35		ns
$E_{on}$		0.4		mJ
$t_{d(off)}$		1.2		mJ
$t_{fi}$		150		ns
$E_{off}$		105		ns
$R_{thJC}$				0.6 K/W
$R_{thCK}$		0.15		K/W



Reverse Diode (FRED) (IXGH40N60CD1 only)		Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
Symbol	Test Conditions	min.	typ.	max.
$V_F$	$I_F = I_T$ , $V_{GE} = 0\text{ V}$ , Note 1			1.3 V 1.8 V
$I_{RM}$	$I_F = I_T$ , $V_{GE} = 0\text{ V}$ , $V_R = 100\text{ V}$ $-di_F/dt = 100\text{ A}/\mu\text{s}$			7.5 A
$t_{rr}$	$I_F = 1\text{ A}$ ; $-di/dt = 100\text{ A}/\mu\text{s}$ ; $V_R = 30\text{ V}$		3.5	ns
$R_{thJC}$				0.90 K/W

Note: 1. Pulse test,  $t_p \leq 300\text{ ms}$ , duty cycle:  $d \leq 2\%$   
2.  $I_T = 40\text{ A}$

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

4,835,592	4,881,106	5,017,508	5,049,961	5,187,117	5,486,715
4,850,072	4,931,844	5,034,796	5,063,307	5,237,481	5,381,025